

Solar Cells Reporting Summary

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► Experimental design

Please check: are the following details reported in the manuscript?

1. Dimensions

- Area of the tested solar cells ☒ Yes ☐ No The area of the tested solar cells (10.4 mm²) can be found in the method section
- Method used to determine the device area ☒ Yes ☐ No The device area was determined through an evaporation mask, see methods

2. Current-voltage characterization

- Current density-voltage (J-V) plots in both forward and backward direction ☐ Yes ☒ No In OPV devices the hysteresis effect is not observed.
- Voltage scan conditions ☒ Yes ☐ No Forward scan - 1V/s - dwell = 20 ms
For instance: scan direction, speed, dwell times
- Test environment ☒ Yes ☐ No The devices were characterized in air at room temperature
For instance: characterization temperature, in air or in glove box
- Protocol for preconditioning of the device before its characterization ☐ Yes ☒ No No preconditioning are necessary for OPV characterizations.
- Stability of the J-V characteristic ☐ Yes ☒ No The stability of the devices is out of the scope of this work.
Verified with time evolution of the maximum power point or with the photocurrent at maximum power point; see ref. 7 for details.

3. Hysteresis or any other unusual behaviour

- Description of the unusual behaviour observed during the characterization ☐ Yes ☒ No No hysteresis was observed in our devices.
- Related experimental data ☐ Yes ☒ No N/A

4. Efficiency

- External quantum efficiency (EQE) or incident photons to current efficiency (IPCE) ☒ Yes ☐ No EQE graph in Figure 1d
- A comparison between the integrated response under the standard reference spectrum and the response measure under the simulator ☒ Yes ☐ No The integrated J_{sc} obtained from the EQE spectra agrees well with the J_{sc} value obtained from the J-V curves under the simulator within 5% deviation
- For tandem solar cells, the bias illumination and bias voltage used for each subcell ☐ Yes ☒ No N/A

5. Calibration

- Light source and reference cell or sensor used for the characterization ☒ Yes ☐ No Calibrated silicon reference cell - part of the commercial solar simulator
- Confirmation that the reference cell was calibrated and certified ☒ Yes ☐ No By supplier of the solar simulator

Calculation of spectral mismatch between the reference cell and the devices under test

☐ Yes
☒ No

Jsc (solar simulator) and Jsc (via EQE) agree within 5 % error

6. Mask/aperture

Size of the mask/aperture used during testing

☒ Yes
☐ No

Device area is determined by a mask with area of 10.4 mm².

Variation of the measured short-circuit current density with the mask/aperture area

☒ Yes
☐ No

No variations observed

7. Performance certification

Identity of the independent certification laboratory that confirmed the photovoltaic performance

☐ Yes
☒ No

This work does not report record efficiency, therefore the photovoltaic performance of our devices were not confirmed from independent certification laboratories.

A copy of any certificate(s)

Provide in Supplementary Information

☐ Yes
☒ No

N/A

8. Statistics

Number of solar cells tested

☒ Yes
☐ No

The average PCE of OSC is obtained from 24 independent devices.

Statistical analysis of the device performance

☒ Yes
☐ No

Statistical results of the devices are shown in Supplementary Table 8.

9. Long-term stability analysis

Type of analysis, bias conditions and environmental conditions

For instance: illumination type, temperature, atmosphere humidity, encapsulation method, preconditioning temperature

☐ Yes
☒ No

Not relevant for this work. However, shelf life of all devices was excellent.